

FIG.1

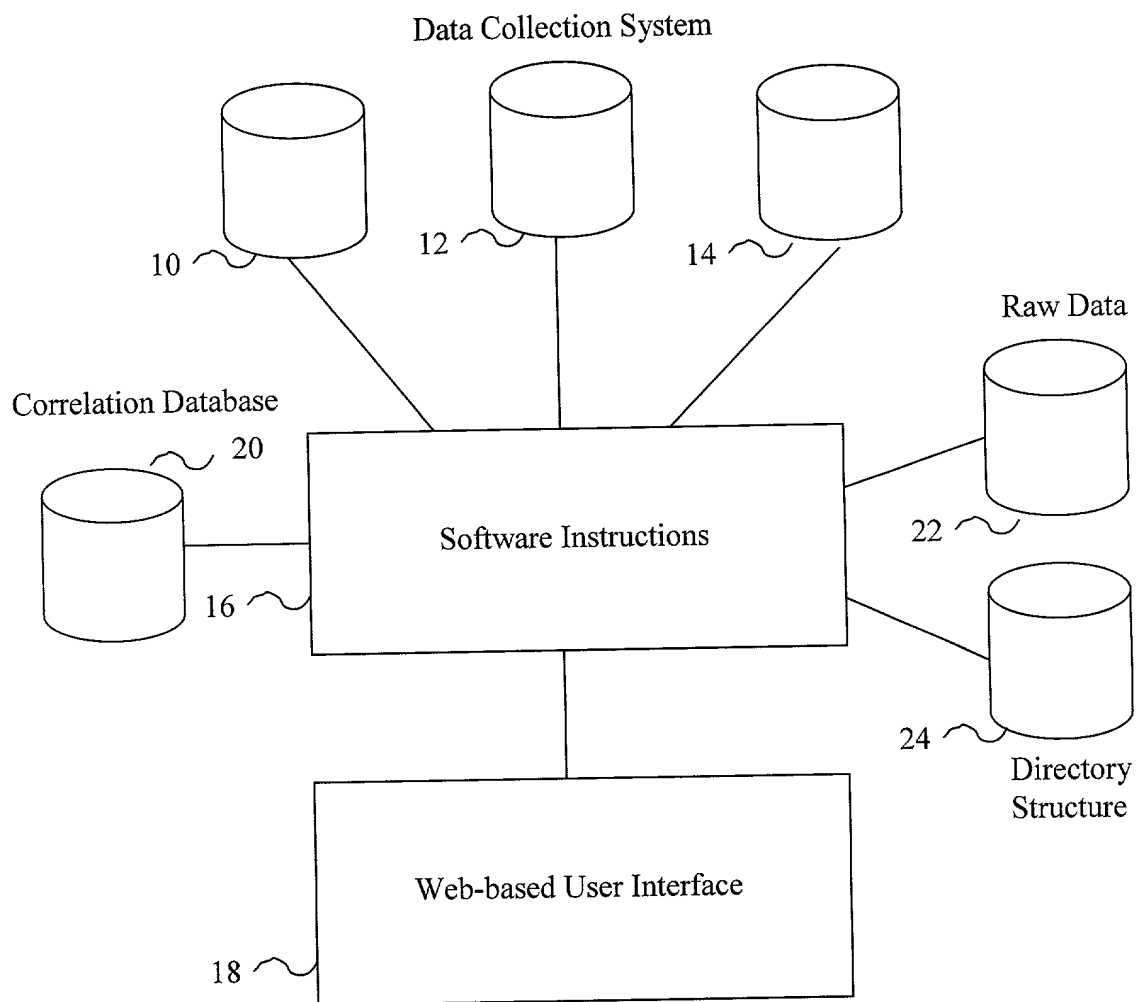


FIG.2

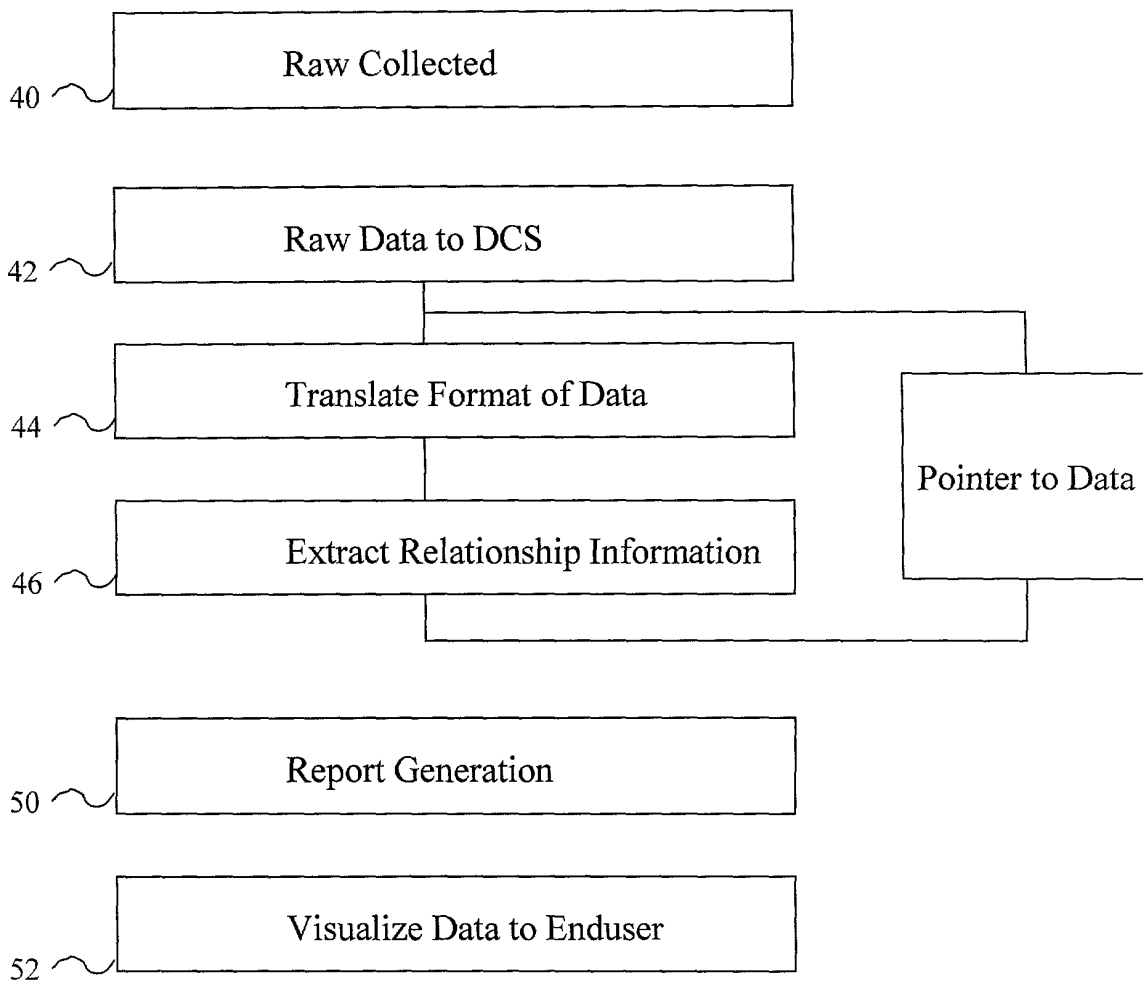


FIG.3

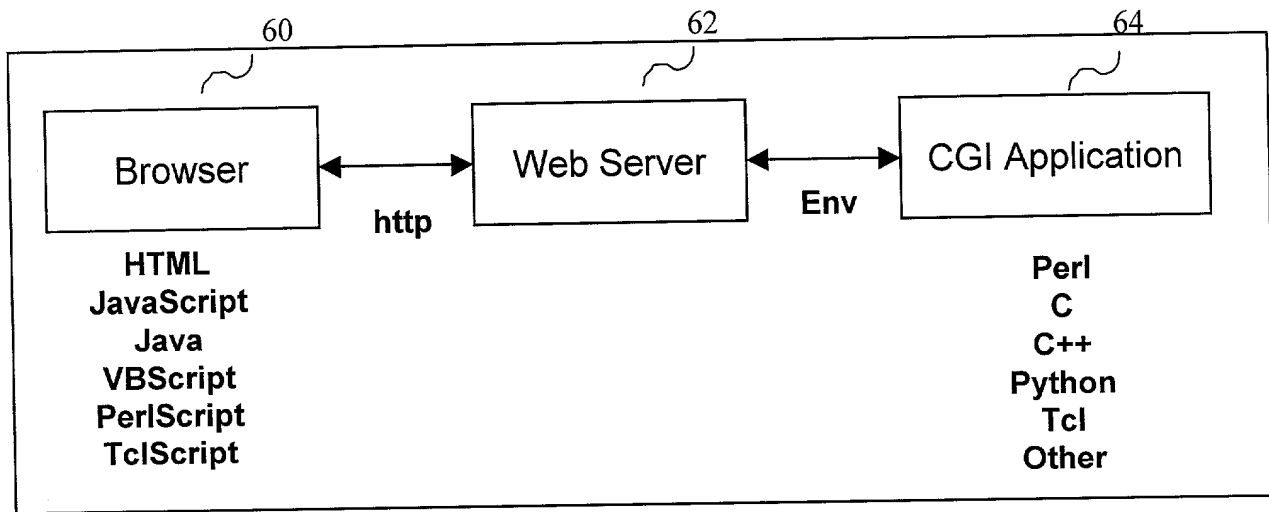


FIG.4

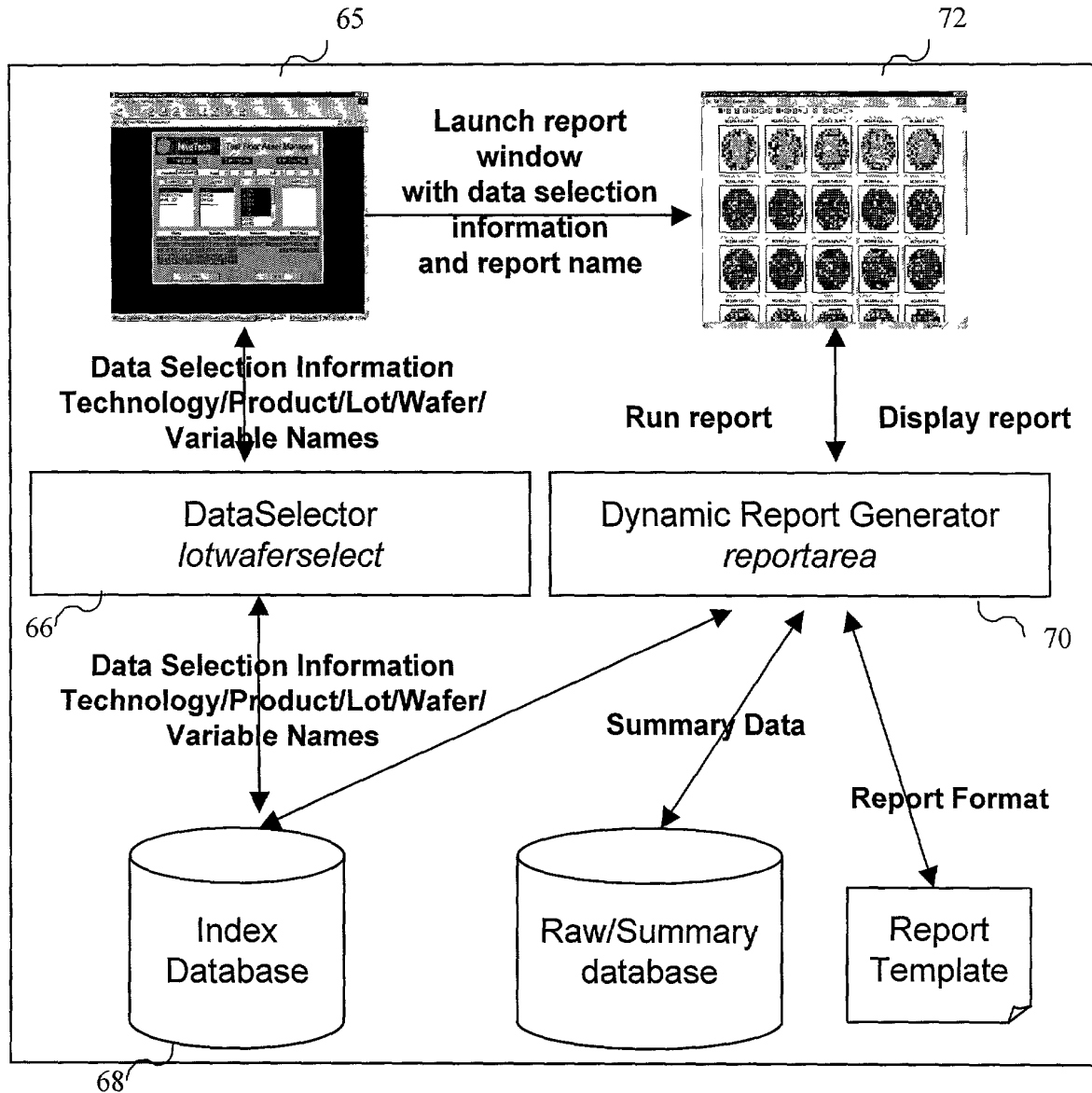


FIG.5

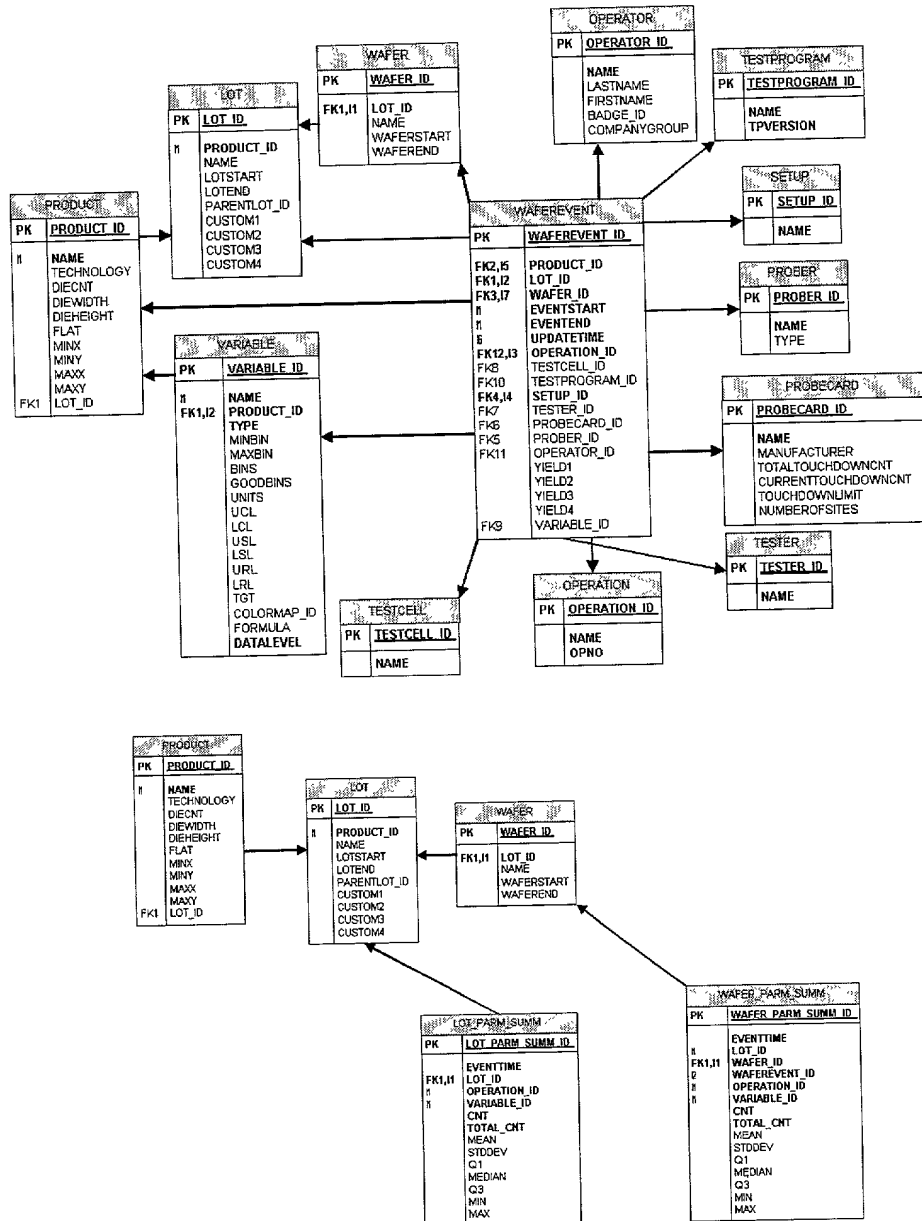


FIG.6

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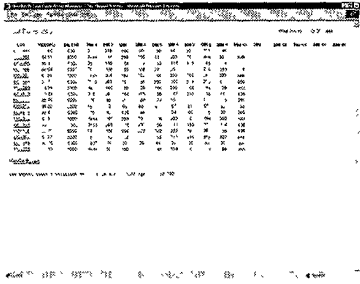
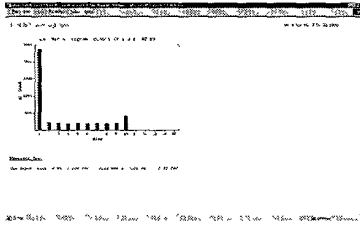
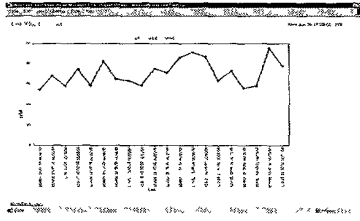
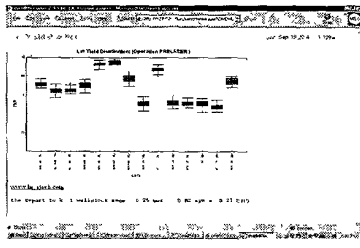
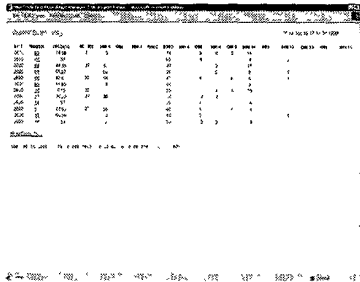
Report Name	Report Description	Example
Lot Summary	<p>A tabular reports that displays the lot bin summary for the selected lots.</p> <p>Click on an individual lot name to drill down to a Wafer Summary report</p>	
Lot Bin Histogram	Bar chart of bin count totals for selected lots.	
Lot Yield Trend	Line trend chart of lot yields of the selected lots.	
Lot Yield Box Plot	Displays the distribution of wafer yields for the selected lots in a single report. The wafer yields are represented as a standard box plot.	
Bin Summary	A tabular report that displays the wafer bin summary for the selected wafers. Click on an individual wafer name to drill down to a Bin Map report.	

FIG.7
(Sheet 1)

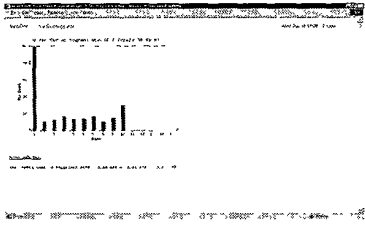
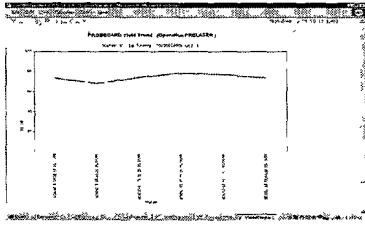
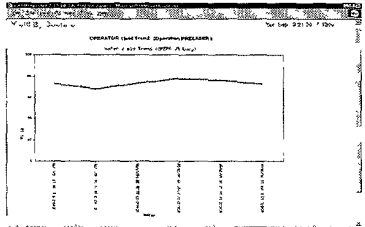
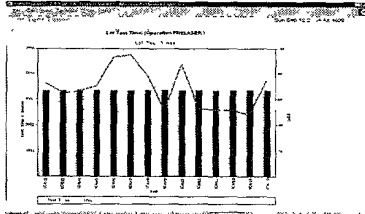
Report Name	Report Description	Example
Wafer Bin Histogram	Bar chart of bin count totals for selected wafers.	
Yield by Probe Card	Line trend chart of wafer yields of all selected wafers, sorted by probe card.	
Yield by Operator	Line trend chart of wafer yields of all selected wafers, sorted by operator.	
Wafer Test Times	A bar chart that plots the actual time taken to test a wafer and the associated yield trend line for that wafer.	No Image Available
Lot Test Times	A bar chart that plots the actual time taken to test a lot, and the associated yield trend line for that lot.	

FIG.7
(Sheet 2)

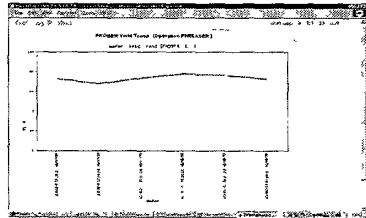
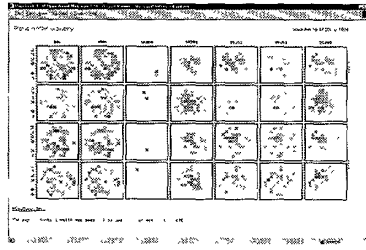
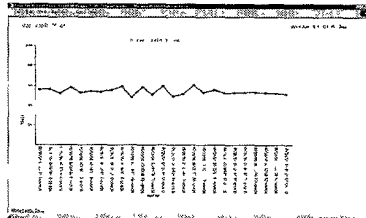
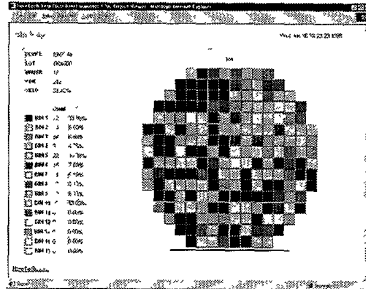
Report Name	Report Description	Example
Yield by Tester	Line trend chart of wafer yields of all selected wafers, sorted by tester.	No Image Available
86		
Yield by Prober	Line trend chart of wafer yields of all selected wafers, sorted by prober.	
86		
Parameter Gallery	Display a table of maps where each column is a parameter and each row is a wafer. Displays wafer maps for all parameters declared for the selected device. Click on an individual wafer map to zoom into that map. Use the browser "Back" button to return to the gallery.	
Wafer Yield Trend	Line trend chart of wafer yields of the selected wafers.	
Bin Map	Displays a bin map of the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected.	
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FIG.7
(Sheet 3)

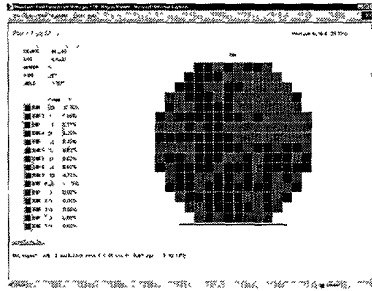
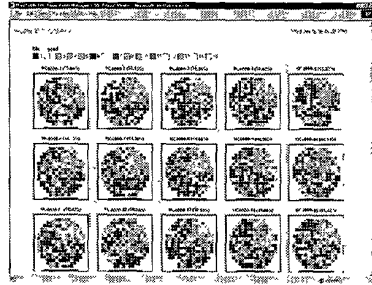
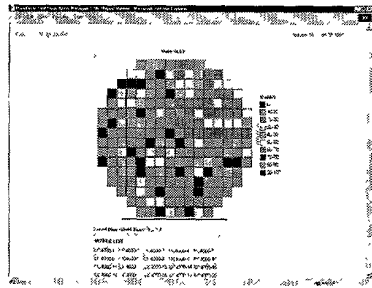
Report Name	Report Description	Example
Pass/Fail Bin Map	Displays a pass/fail map for the selected wafers. This report uses the device configuration information to determine the pass bins. Displays maps for all wafers in the selected lots if no individual wafers are selected.	
Bin Gallery	Displays a pass/fail map for the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. Click on an individual wafer map to zoom into that map.	
Percent Composite	Displays a composite yield map for the selected wafers. This report uses the device configuration information to determine the pass bins.	

FIG.7
(Sheet 4)

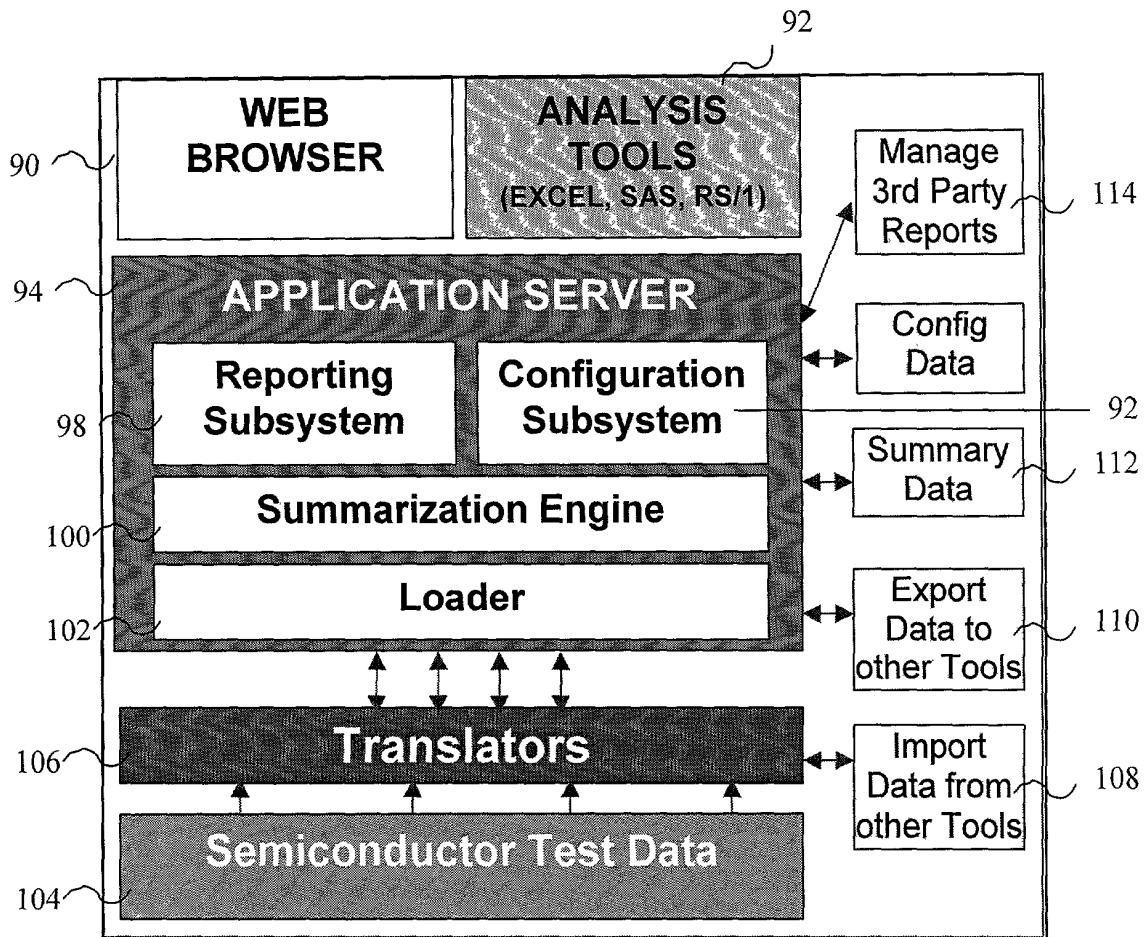


FIG.8

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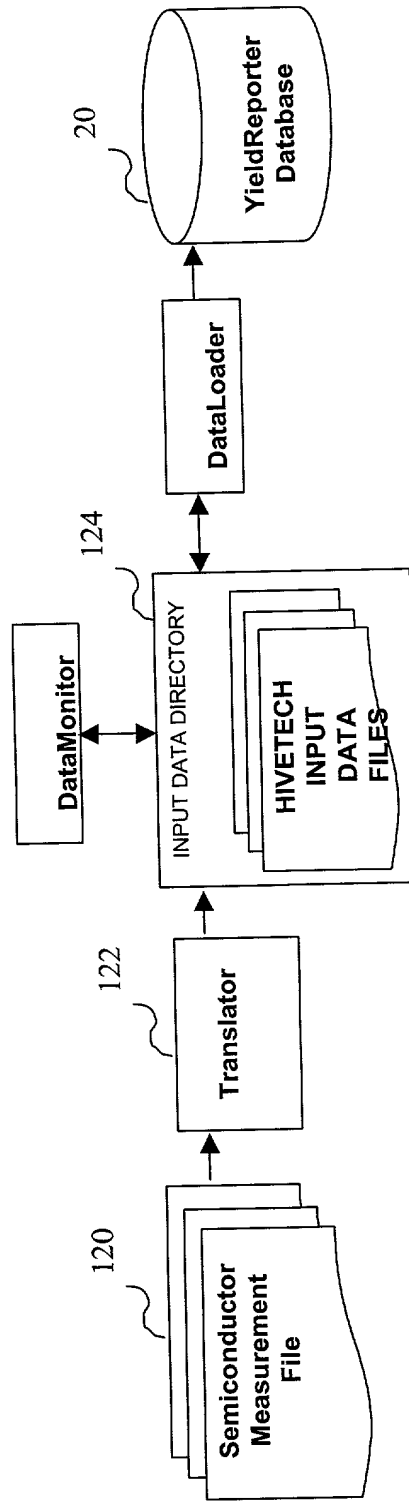
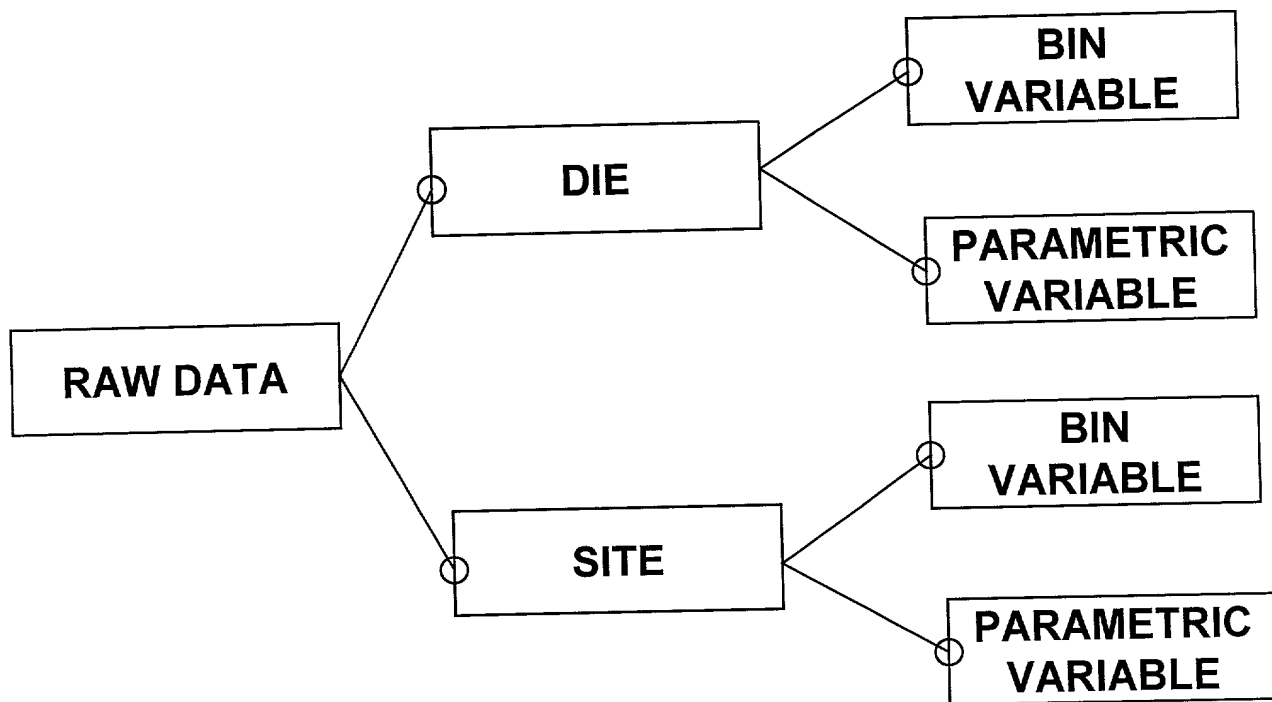
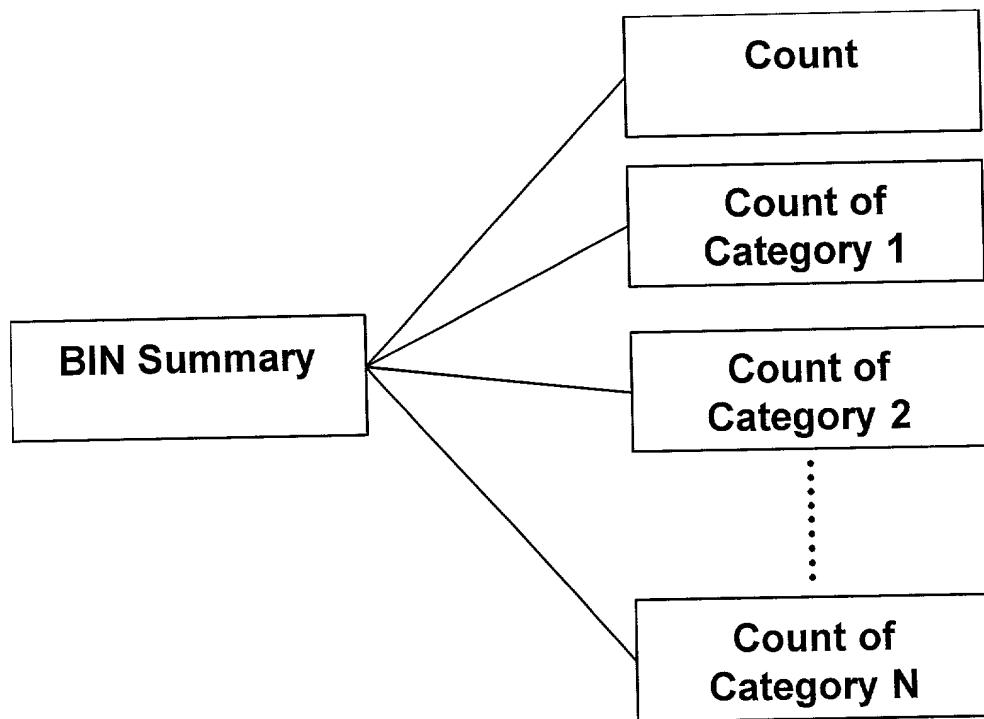


FIG.9



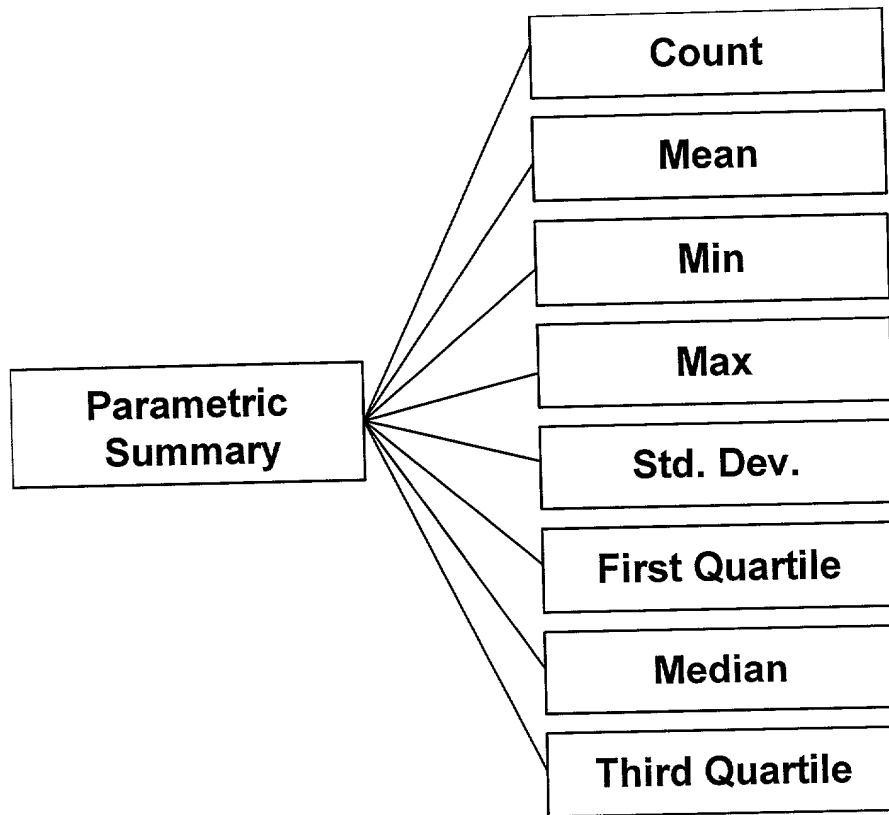
Variable Types

FIG.10A



Lot or Wafer Bin Summary

FIG.10B



Lot or Wafer Parametric Summary

FIG.10C